

Search Notes



Application/Control No.

10/711,201

Examiner

Ernest F. Karlsen

Applicant(s)/Patent under Reexamination

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Art Unit

2829

SEARCHED

Class	Subclass	Date	Examiner
324	765	5/26/2005	E.F.K.
716	4	5/26/2005	E.F.K.
702	81 84	5/26/2005	E.F.K.
700	110	5/26/2005	E.F.K.
438	14	5/26/2005	E.F.K.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
calculat\$ adj yield and wafer PLUS SEARCH	5/26/2005	E.F.K.